

**Search Notes**

Application/Control No.

09/720,720

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

SPITZ ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	63	11/15/2006	BT
216	79	11/15/2006	BT
438	80	11/15/2006	BT
438	719	11/15/2006	BT

**INTERFERENCE SEARCHED**

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216	63	11/15/2006	BT
216	79	11/15/2006	BT
216	80	11/15/2006	BT
438/719		11/15/2006	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR